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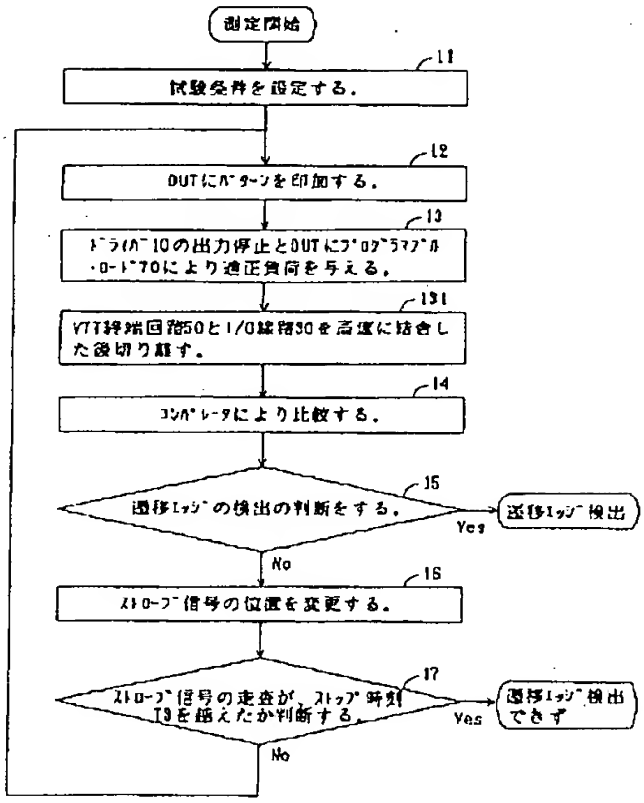
TITLE : I/O PIN MEASURING METHOD IN IC TEST SYSTEM



ABSTRACT : PROBLEM TO BE SOLVED: To detect the transition edge of output pulse from a DUT(device under test) and the high impedance state of the DUT.

SOLUTION: In order to quicken the settling to a termination voltage by discharging the I/O line of an I/O pin measuring circuit quickly, a VTT termination circuit is connected with the I/O line at a high speed and then they are disconnected. When the transion edge of output pulse from a DUT is detected, step 13 is performed in the way of sequential execution from measuring step 11 to step 17 and a measuring step 131, which makes a control.VTT termination signal high level and then low level after interruption of output from a driver, is provided between measuring steps 13, 14 as a control means. Means for detecting the transion edge of output pulse from the DUT and the high impedance state thereof is also provided.